

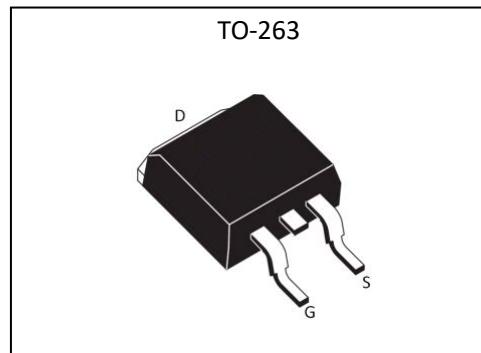
Silicon N-Channel Power MOSFET
General Description:

The HMD120N10 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. The package form is TO-263, which accords with the RoHS standard.

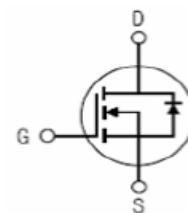
V_{DSS}	100	V
I_D	120	A
P_D	200	W
$R_{DS(ON)}\text{type}$	4.5	$\text{m}\Omega$

Features:

- $R_{DS(ON)} < 6\text{m}\Omega$ @ $V_{GS}=10\text{V}$ (Typ4.5mΩ)
- High density cell design for ultra low $R_{ds(on)}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation


Applications:

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

Inner Equivalent Principium Chart

Absolute (T_c= 25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage ^{a1}	100	V
I_D	Continuous Drain Current ^{a2}	120	A
I_{DM}	Pulsed Drain Current ^{a2a4}	480	A
V_{GS}	Gate-to-Source Voltage	± 20	V
P_D	Power Dissipation	200	W
E_{AS}	Single pulse avalanche energy ^{a5}	850	mJ
T_J, T_{stg}	Operating Junction and Storage Temperature Range	175, -55 to 175	°C

Electrical Characteristics (T_c=25°C unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	100	--	--	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =100V, V _{GS} = 0V, T _a = 25°C	--	--	5.0	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =+20V	--	--	0.1	μA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =-20V	--	--	-0.1	μA

ON Characteristics ^{a3}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DSON}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =60A	--	4.5	6.0	mΩ
V _{GTH}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.0	--	3.0	V
Pulse width tp≤380μs, δ≤2%						

Dynamic Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} =10V, I _D =60A	70	--	--	S
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =25V	--	530	--	pF
C _{oss}	Output Capacitance	f=1.0MHz	--	550	--	
C _{rss}	Reverse Transfer Capacitance		--	25	--	

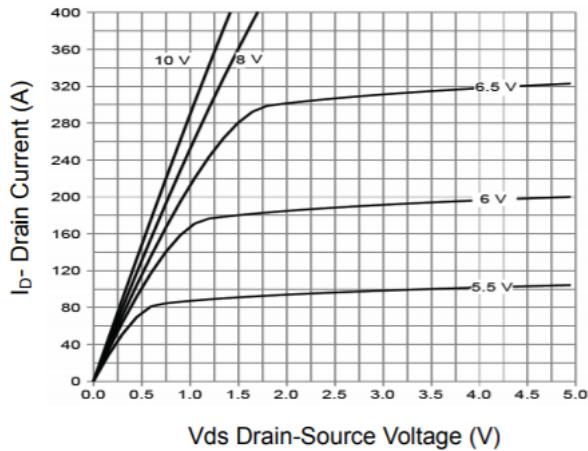
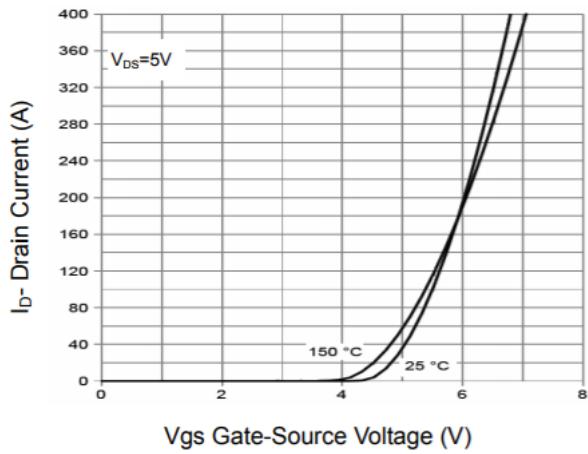
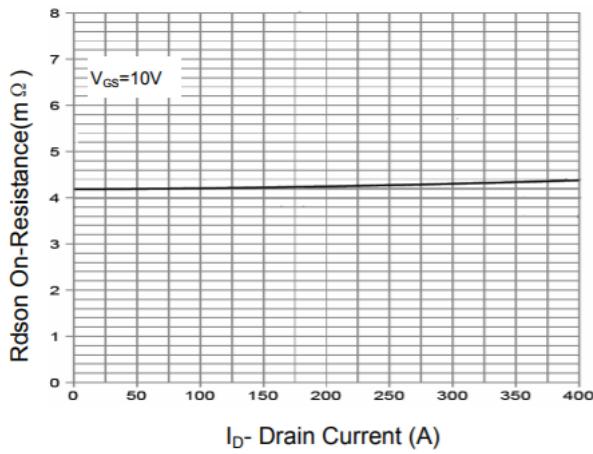
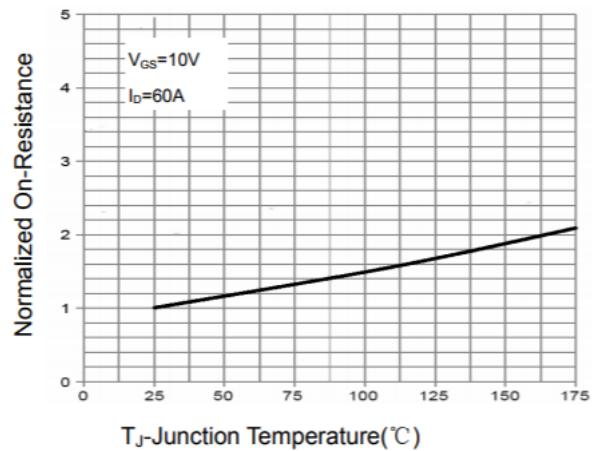
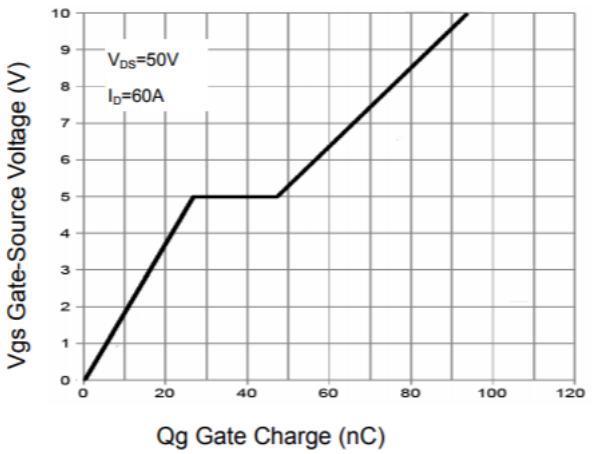
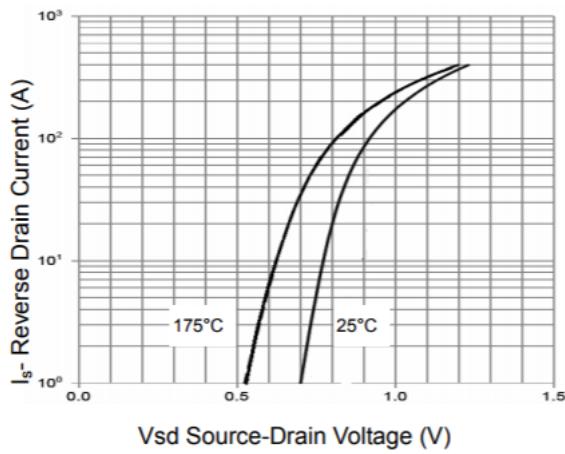
Resistive Switching Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	V _{DD} =50V, I _D =60A	--	20	--	ns
t _r	Rise Time		--	13	--	
t _{d(OFF)}	Turn-Off Delay Time		--	40	--	
t _f	Fall Time		--	12	--	
Q _g	Total Gate Charge	V _{DD} =50V, I _D =60A	--	90	--	nC
Q _{gs}	Gate to Source Charge		--	25	--	
Q _{gd}	Gate to Drain ("Miller")Charge		--	20	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I _S	Continuous Source Current ^{a2} (Body Diode)		--	--	120	A
V _{SD}	Diode Forward Voltage	I _S =120A, V _{GS} =0V	--	--	1.5	V
T _{rr}	Reverse Recovery Time	T _J = 25°C, IF =60A di/dt = 100A/μs	--	70	--	ns
Q _{rr}	Reverse Recovery Charge		--	140	--	nc

Symbol	Parameter	Typ.	Units
R _{θJC}	Junction-to-Case ^{a2}	0.75	°C/W

^{a1}: T_J=+25°C to +175^{a2}: Silicon limited current only..^{a3}: Package limited current.^{a4}: Repetitive rating; pulse width limited by maximum junction temperature.^{a5}: Pulse width≤380μs; duty cycle≤2%.

Characteristics Curve :

Figure 1 Output Characteristics

Figure 2 Transfer Characteristics

Figure 3 Rdson- Drain Current

Figure 4 Rdson-Junction Temperature

Figure 5 Gate Charge

Figure 6 Source- Drain Diode Forward

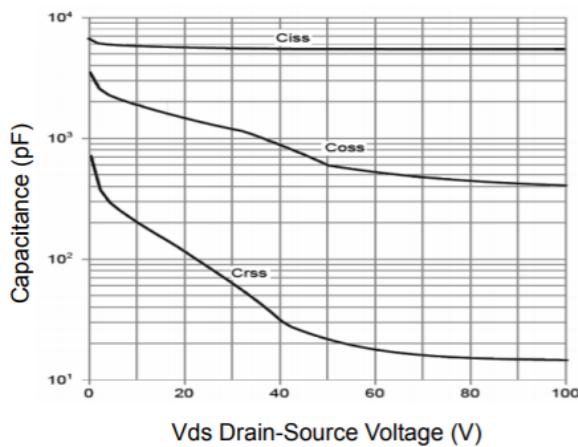


Figure 7 Capacitance vs Vds



Figure 9 Power De-rating

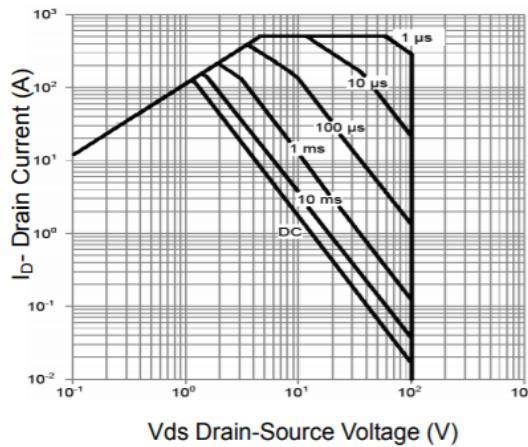


Figure 8 Safe Operation Area

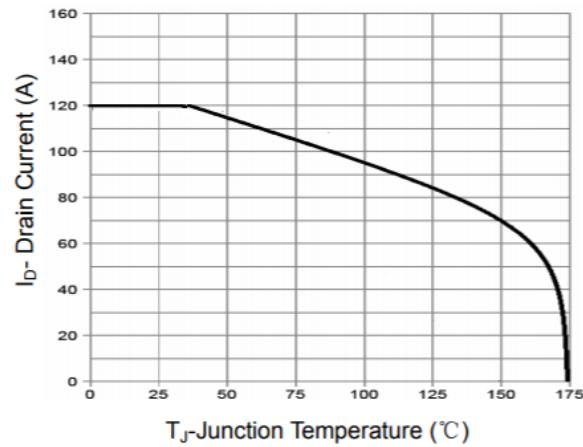


Figure 10 Current De-rating

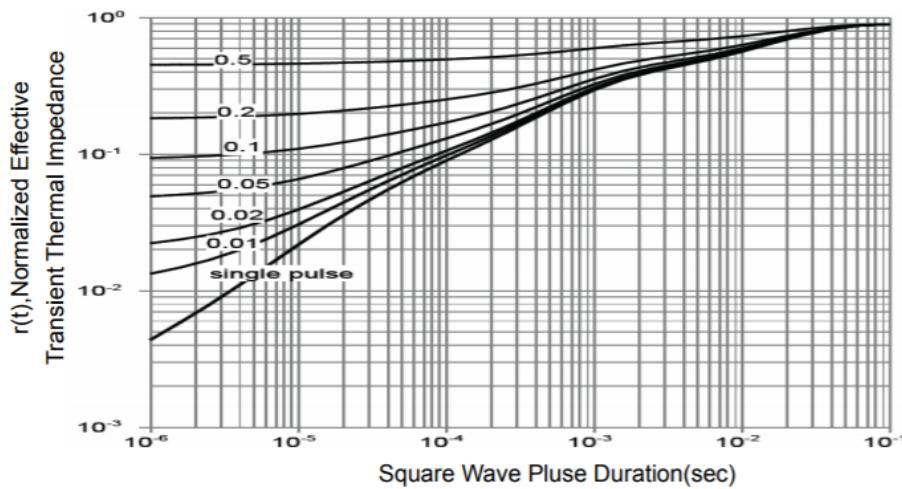


Figure 11 Normalized Maximum Transient Thermal Impedance